

## FDS8958A

# **Dual N & P-Channel PowerTrench® MOSFET**

### **General Description**

These dual N- and P-Channel enhancement mode power field effect transistors are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state ressitance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

### **Features**

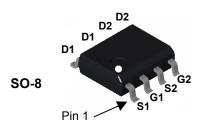
Q1: N-Channel

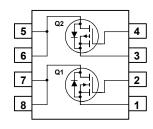
7.0A, 30V 
$$R_{DS(on)} = 0.028\Omega @ V_{GS} = 10V$$
  $R_{DS(on)} = 0.040\Omega @ V_{GS} = 4.5V$ 

• Q2: P-Channel

-5A, -30V 
$$R_{DS(on)} = 0.052\Omega$$
 @  $V_{GS} = -10V$  
$$R_{DS(on)} = 0.080\Omega$$
 @  $V_{GS} = -4.5V$ 

- Fast switching speed
- High power and handling capability in a widely used surface mount package





### Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	30	V
V <sub>GSS</sub>	Gate-Source Voltage		±20	±20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	7	-5	Α
	- Pulsed		20	-20	
P <sub>D</sub>	Power Dissipation for Dual Operation		2	W	
	Power Dissipation for Single Operation	(Note 1a)	1.	6	
		(Note 1b)	1		
		(Note 1c)	0.	9	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to	+150	°C

## **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

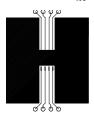
-	Device Marking	Device	Reel Size	Tape width	Quantity
-	FDS8958A	FDS8958A	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Cha	racteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ = 0 V, $I_{D}$ = 250 $\mu$ A $V_{GS}$ = 0 V, $I_{D}$ = -250 $\mu$ A	Q1 Q2	30 -30			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C $I_D$ = -250 μA, Referenced to 25°C	Q1 Q2		25 -22		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V V <sub>DS</sub> = -24 V, V <sub>GS</sub> = 0 V V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V	Q1 Q2			1 -1	μΑ
$I_{GSSF}$	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	All			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V	All			-100	nA
On Chai	racteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$ $V_{DS} = V_{GS}, I_D = -250 \mu A$	Q1 Q2	1 -1	1.6 -1.7	3 -3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C $I_D$ = -250 μA, Referenced to 25°C	Q1 Q2		-4.3 4		mV/°C
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 7 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 7 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = 4.5 \text{ V}, I_D = 6 \text{ A}$	Q1		21 32 27	28 42 40	mΩ
		$V_{GS}$ = -10 V, $I_D$ = -5 A $V_{GS}$ = -10 V, $I_D$ = -5 A, $T_J$ = 125°C $V_{GS}$ = -4.5 V, $I_D$ = -4 A	Q2		41 58 58	52 78 80	
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$ $V_{GS} = -10 \text{ V}, V_{DS} = -5 \text{ V}$	Q1 Q2	20 -20			Α
<b>g</b> FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_D = 7 \text{ A}$ $V_{DS} = -5 \text{ V}, I_D = -5 \text{ A}$	Q1 Q2		19 11		S
Dynami	c Characteristics						
C <sub>iss</sub>	Input Capacitance	Q1 V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz	Q1 Q2		789 690		pF
C <sub>oss</sub>	Output Capacitance	Q2	Q1 Q2		173 306		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$	Q1 Q2		66 77		pF

Electri	cal Characteristics	(continued) T <sub>A</sub> = 25°C unless other	wise noted				
Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Switchir	ng Characteristics (Note	2)					
$t_{\text{d(on)}} \\$	Turn-On Delay Time	Q1 V <sub>DD</sub> = 10 V, I <sub>D</sub> = 1 A,	Q1 Q2		2.2 6.7	4.4 13.4	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ = 10V, $R_{GEN}$ = 6 $\Omega$	Q1 Q2		7.5 9.7	15 19.4	ns
$t_{\text{d(off)}} \\$	Turn-Off Delay Time	Q2 V <sub>DD</sub> = -10 V, I <sub>D</sub> = -1 A,	Q1 Q2		11.8 19.8	21.3 35.6	ns
t <sub>f</sub>	Turn-Off Fall Time	$V_{GS}$ = -10V, $R_{GEN}$ = 6 $\Omega$	Q1 Q2		3.7 12.3	7.4 22.2	ns
Qg	Total Gate Charge	Q1 V <sub>DS</sub> = 15 V, I <sub>D</sub> = 7 A, V <sub>GS</sub> = 10 V	Q1 Q2		16 14	26 23	nC
Q <sub>gs</sub>	Gate-Source Charge	Q2	Q1 Q2		2.5 2.2		nC
$Q_{gd}$	Gate-Drain Charge	$V_{DS} = -15 \text{ V}, I_{D} = -5 \text{ A}, V_{GS} = -10 \text{ V}$	Q1 Q2		2.1		nC
Drain-S	ource Diode Character	istics and Maximum Ratings	;				
Is		Source Diode Forward Current	Q1 Q2			1.3 -1.3	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = -1.3 \text{ A}$ (Note 2)	Q1 Q2		0.74 -0.76	1.2 -1.2	V

#### Notes:

1.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a) 78°/W when mounted on a 0.5 in² pad of 2 oz copper



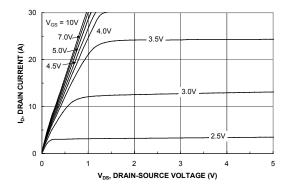
b) 125°/W when mounted on a .02 in² pad of 2 oz copper



c) 135°/W when mounted on a minimum pad.

Scale 1: 1 on letter size paper

2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%



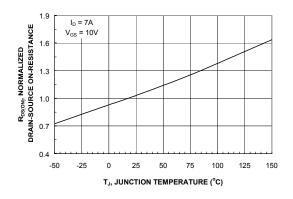
2.4

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Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



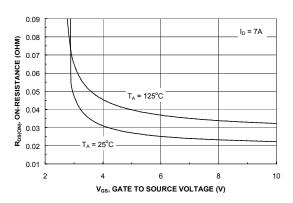
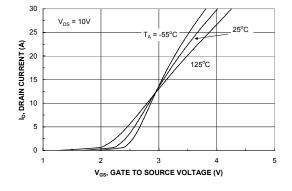


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



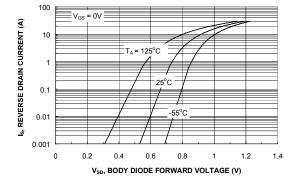
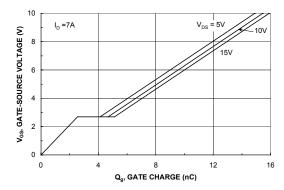


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.



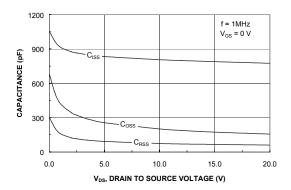
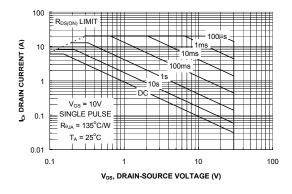


Figure 7. Gate Charge Characteristics.





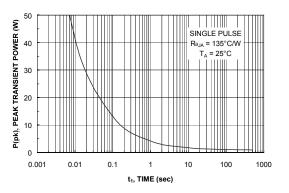


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

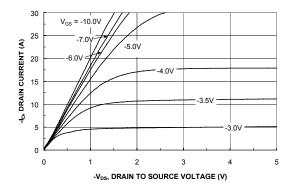


Figure 11. On-Region Characteristics.

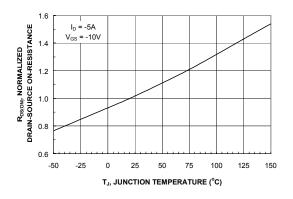


Figure 13. On-Resistance Variation with Temperature.

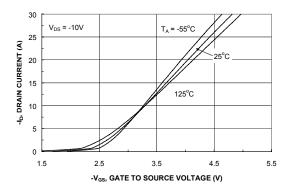


Figure 15. Transfer Characteristics.

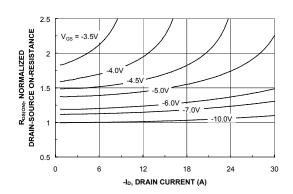


Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.

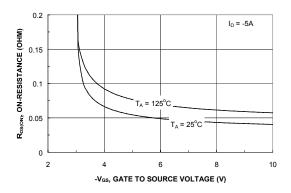


Figure 14. On-Resistance Variation with Gate-to-Source Voltage.

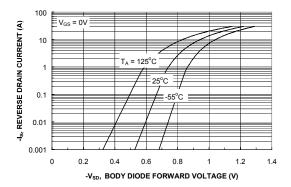
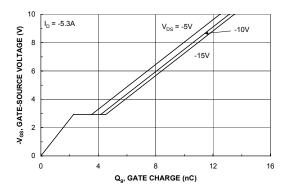


Figure 16. Body Diode Forward Voltage Variation with Source Current and Temperature.



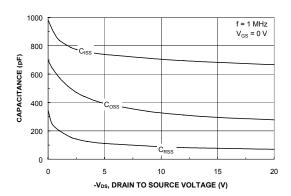
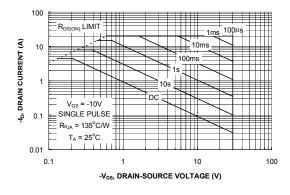


Figure 17. Gate Charge Characteristics.





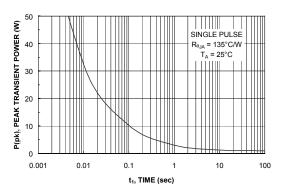


Figure 19. Maximum Safe Operating Area.

Figure 20. Single Pulse Maximum Power Dissipation.

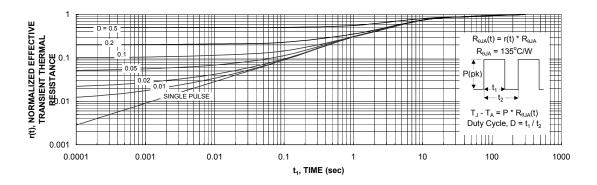


Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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